

<b>Search Notes</b> 				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/538,540	MIHAN ET AL.	
				Examiner	Art Unit	
				Rip A. Lee	1713	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
528	396	03-28-2006 M				
526	349					
526	352					
526	169					
526	192					
526	161					
526	129					
502	103	03-29-2006 M				
502	104	03-29-2006 M				
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			